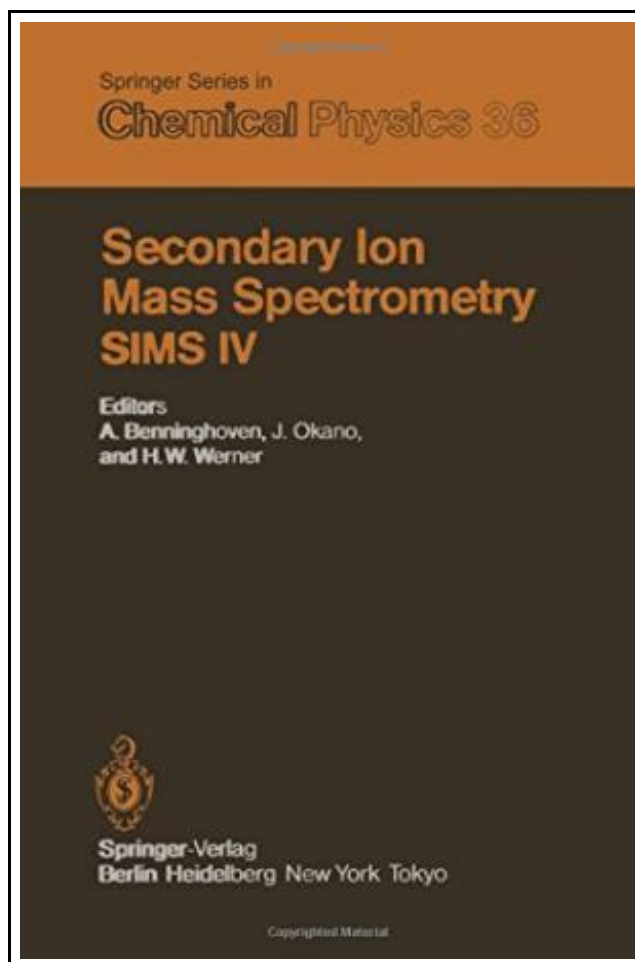


Secondary Ion Mass Spectrometry SIMS IV



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(Juliet Mertz)

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